

**Search Notes**

Application/Control No.

10/527,376

Examiner

Erich A. Leeser

Applicant(s)/Patent under  
Reexamination

SHIMADA ET AL.

Art Unit

1624

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
EAST 514/257, 250; 544/250-251, 234, 344 & 346 see printout			

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STN structure search	7/30/2007	EL
PALM inventor search	7/30/2007	EL
EAST 514/257, 250; 544/250-251, 234, 344 and 346 with search terms, see printout	7/30/2007	EL